

Abstracts

Quasi-Simultaneous External Electrooptic Probing of Transverse and Longitudinal Field Distributions Taking Into Account the Probe Tip Invasiveness

W. Thomann and P. Russer. "Quasi-Simultaneous External Electrooptic Probing of Transverse and Longitudinal Field Distributions Taking Into Account the Probe Tip Invasiveness." 1994 MTT-S International Microwave Symposium Digest 94.3 (1994 Vol. III [MWSYM]): 1601-1604.

A versatile electrooptic measurement setup facilitates the direct probing of circuits on electrooptic substrates and on arbitrary substrates by employing an external probe tip of a specific crystal-cut that allows the quasi-simultaneous probing of transverse and quasi-longitudinal electric field components. Employing the presented quasi-simultaneous measurements and the theoretical methods, the determined change in intensity of the transmitted laser beam can be used for the implementation of correction algorithms in the space-domain and time-domain. As examples we use microstrip lines and coupled microstrip transmission lines.

[Return to main document.](#)